

Atom Probe Tomography: Applications and Techniques

Tuesday, August 15, 2017 from 11:45am - 1:15pm Marcus Nanotechnolgy Conference Rooms 1117

Atom Probe Tomography (APT) is the highest spatial resolution analytical characterization technique with high efficiency single atom detection for quantitative atomic scale 3D elemental mapping of chemical heterogeneities. Learn more about this technique and how it may be applied to your research at this event.





Agenda Topics:

Atom Probe Tomography (APT): Operational Theory Introduction to APT Data Reduction

Introduction to APT Sample Preparation APT Applications

- Metals: Integration with Advanced Modeling
- Ceramics, high performance materials
- Semiconductor Devices: Planar and finFET, LED Devices, III/V
- Geological Materials and Biominerals

Correlative synergy



- t-EBSD
- TEM
- EPMA

Atom Probe Tomography Instrumentation

VISUALIZING THE NEXT

Lunch will be provided.

Register at: ien.gatech.edu/prof-dev

Attendance is free of charge but space is limited! To register, please complete the registration form by August 8th 2017

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Dan Lawrence

Representing Atom Probe Tomography Instrumentation for CAMECA Instruments, Inc.

Dan has nearly 20 years of materials analysis experience, first as a staff member at the University of Wisconsin in Madison-WI then as an engineer at IBM microelectronics foundry in Burlington, VT. Since 2005, Dan has worked with Atom Probe Tomography instrumentation from within the applications group and most recently as a technical sales specialist at CAMECA.